

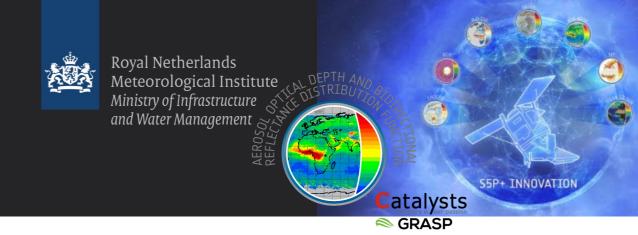
Development of TROPOMI Directional Lambertian Equivalent Reflectivity (DLER) and Aerosol Optical Thickness (AOT) products

M. de Graaf & L.G. Tilstra (KNMI)

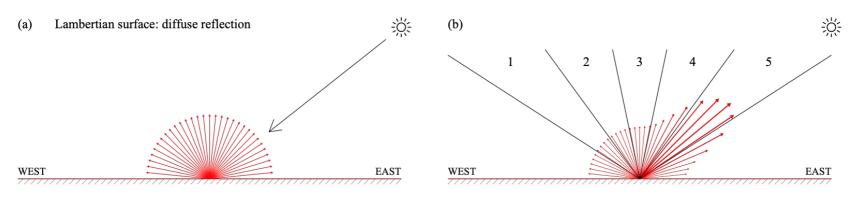






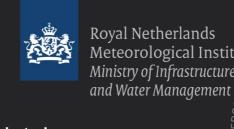


Directional Lambertian Equivalent Reflectivity (DLER)





Royal Netherlands Meteorological Institute Ministry of Infrastructure and Water Management





GRASP

ESA EOP-SDR initiative (IT)

TROPOMI surface DLER database features

21 one-nm wide wavelengths from UV to NIR

Monthly 0.125°x0.125° grids of directional minimal reflectivity

Cloud screening based on NPP VIIRS cloud product

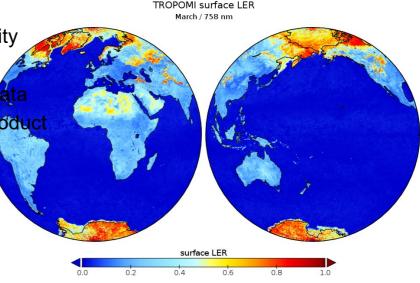
DLER current version (v0.7) based on 3 years of mission data

Daily L1 to L2 processing on S5P-PAL of L2 SCNLER product

Monthly L2 to L3 processing step executed on S5P-PAL

DLER database now contains validated data

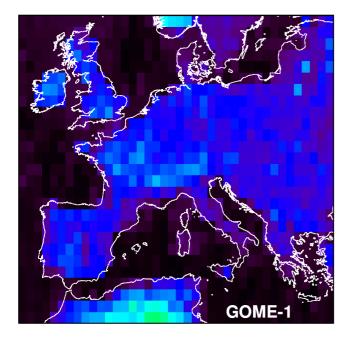
Documentation (ATBD v1.1.0; PUM v0.1.0; VR v1.1.0) all available

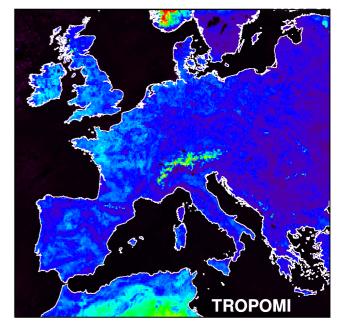


TROPOMI_Sentinel-5P_0125x0125_surface_LER_v0.2-beta.nc

Spatial resolution compared to previous surface albedo databases: 5.3)







GOME-1: 1° × 1°

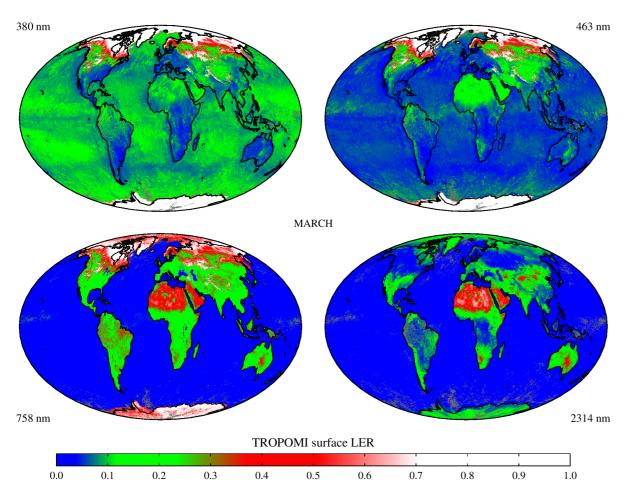
Too low resolution, ragged coastlines Cloud contamination Low quality

GOME-2: 0.25° × 0.25° Note: real intrinsic resolution varies via dynamic gridding techniques between 0.25° × 0.25° and 1° × 1°

TROPOMI: 0.125° × 0.125° Huge increase of information content

Examples of LER fields before post-processing (1)





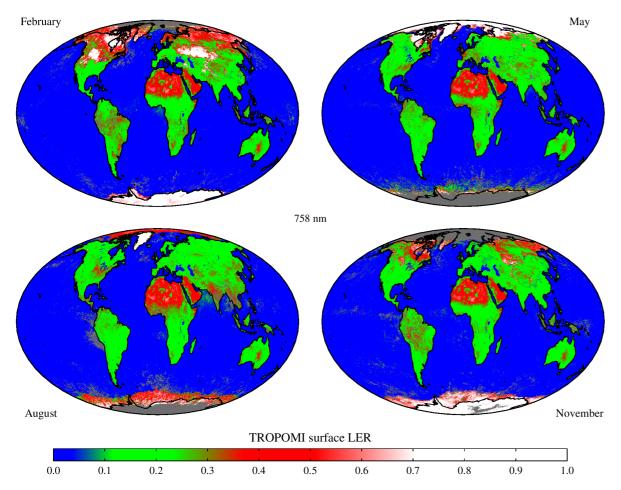
Gray = missing pixels

One year of data used.

Qualitatively ok.

Examples of LER fields before post-processing (2)





Gray = missing pixels

One year of data used.

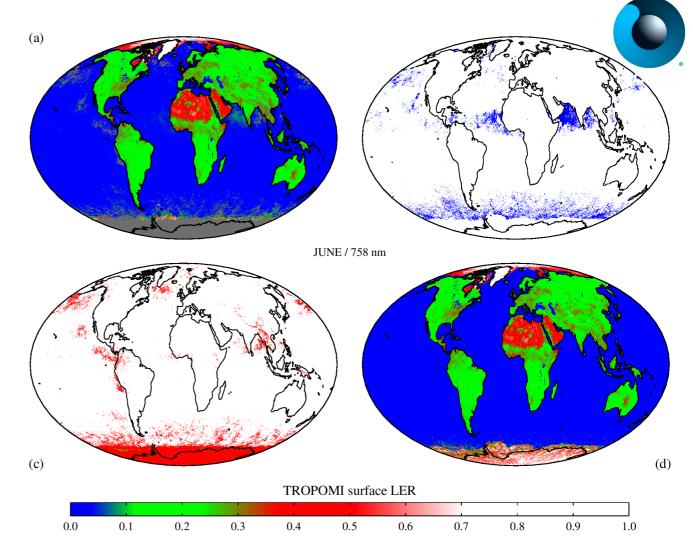
Qualitatively ok.

Post-processing needed.

Post-processing steps

(ATBD: Sect. 6.4 / Fig. 9)

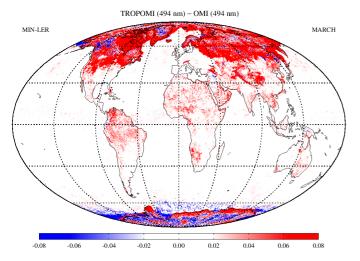
- (a) before postprocessing
- (b) cloud contamination
- (c) missing data
- (d) after post-processing



(based on 1 year of data)

Comparison with other surface LER databases: 494 nm

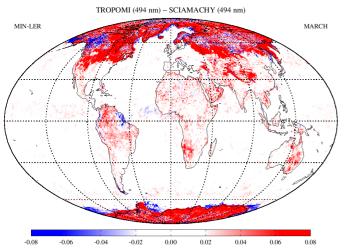


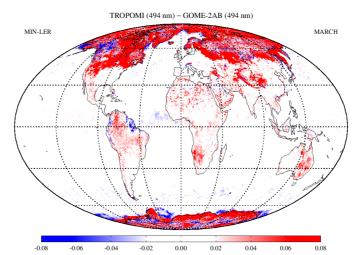


Good agreement, overestimation can be explained by known calibration problems.

Cloud contamination is visible in some parts over the ocean.

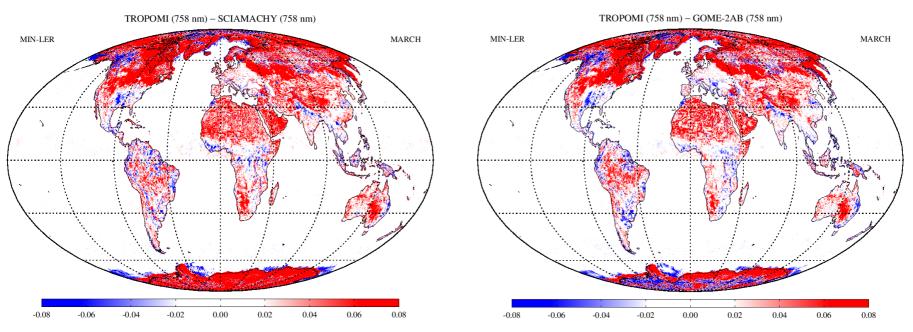
Only one year of TROPOMI data used!





Comparison with other surface LER databases: 758 nm

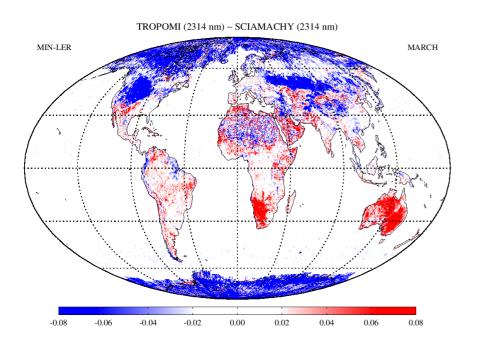




Good agreement, overestimation can partly be explained by known calibration problems. Only one year of TROPOMI data used!

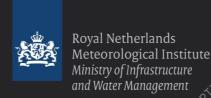
Comparison with other surface LER databases: 2314 nm





Fair agreement, deviations can only partly be explained by known calibration problems. Only one year of TROPOMI data used!



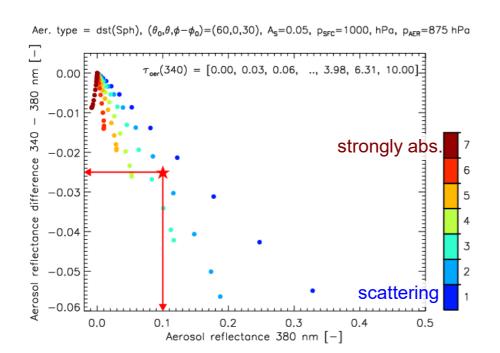


SENTINEL-5P+ INNOVATION

ESA EOP-SDR initiative (IT)

S5P-TROPOMI AER OT PRODUCT

Global aerosol optical thickness and single scattering albedo



Catalysts

TROPOMI AOT is based on
LUT approach, based on OMI AOT
Retrieved in UV at 340, 380, 416, 440, 494 nm
Dust model is based on spheroids

Inputs:

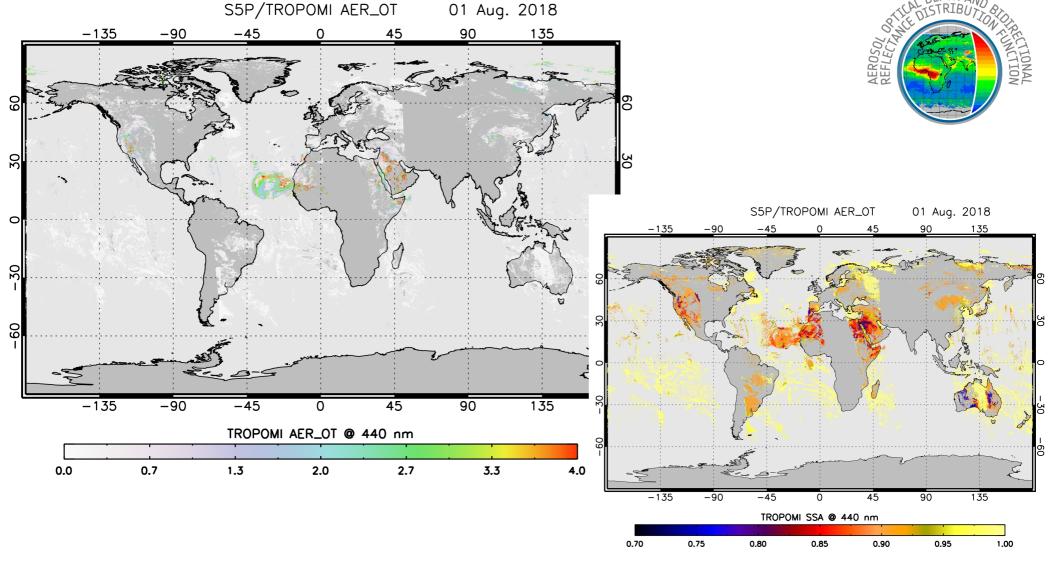
- VIIRS Cloud fraction
- S5P DLER
- CO, AAI and surface type for Aerosol model selection

S5P+ INNOVATION

 CAMS model scale height for Aerosol height (to be changed to ALH)

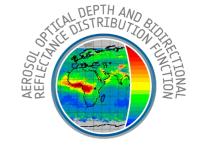
Output:

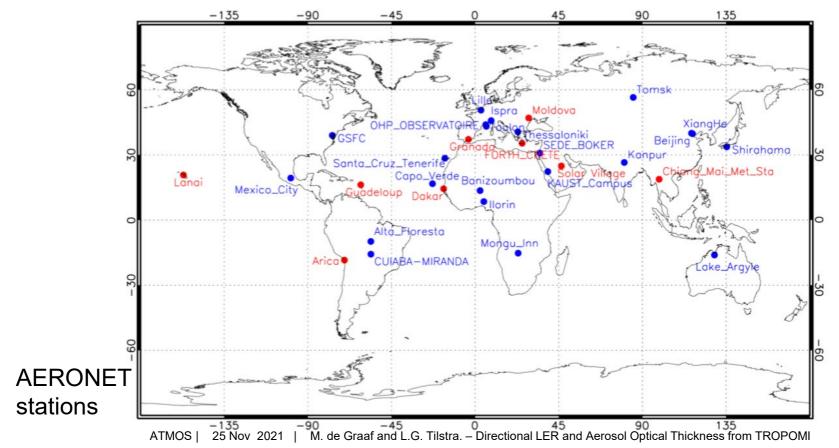
L2 files in standard S5P format (NetCDF)

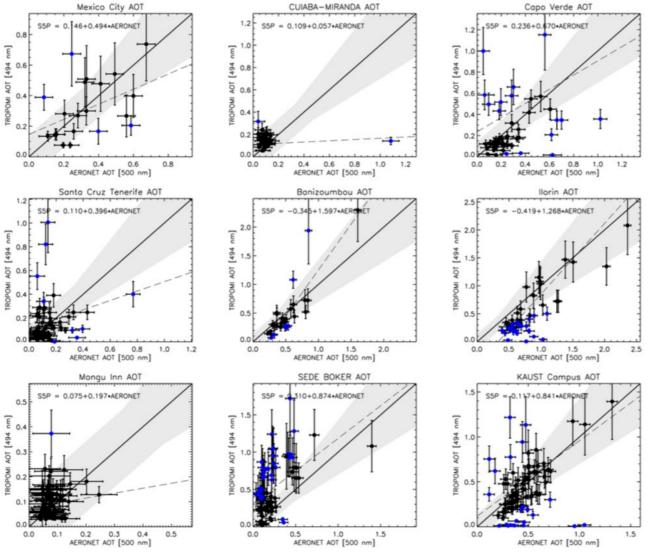


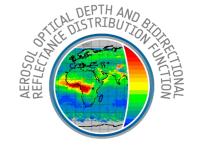
ATMOS | 25 Nov 2021 | M. de Graaf and L.G. Tilstra. – Directional LER and Aerosol Optical Thickness from TROPOMI







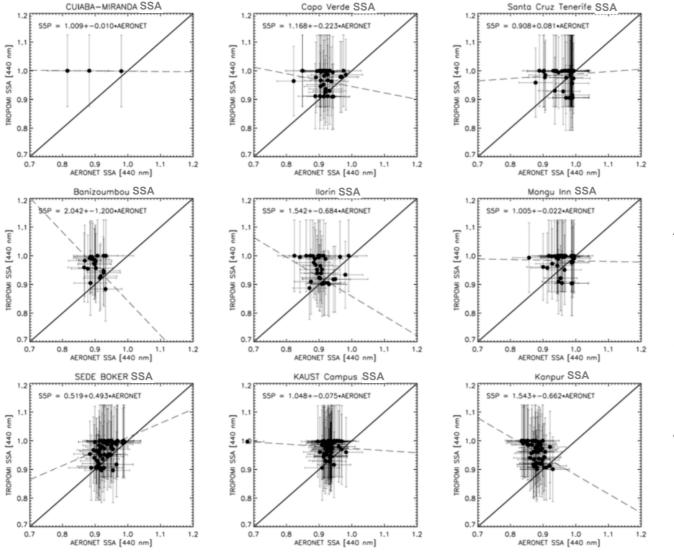


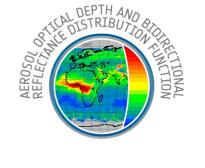


AERONET vs TROPOMI AOT:

S5P <200 km, < 15 min processed on PAL.

AERONET: Version 3, Level 1.5





AERONET vs TROPOMI SSA:

S5P <200 km, < 15 min processed on PAL.

AERONET: Version 3, Level 1.5



Complete TROPOMI aerosol product suite:

Absorbing Aerosol Index (S5P-AAI):

- Degradation corrected in V2 (D. Stein-Zweers)
- New definitions will be introduced to account for cloud effects

Aerosol Layer Height (S5p_ALH):

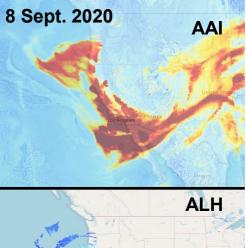
- New, fast, global operational product
- Global, based on VIIRS cloud mask
- Over land accuracy should be improved.

Aerosol Optical Thickness and Single Scattering Albedo in UV (S5p_AOT):

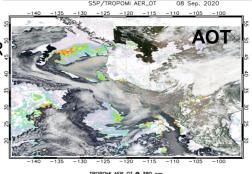
- Based on OMI OMAERO and OMAERUV algorithms in UV: 340, 380, 416, 440, 496 nm
- Uses S5P input (CO, AAI, LER), will be improved to include S5P-ALH and S5P DLER
- Cloud fraction from VIIRS

ATMOS I

All these aerosol products should provide a consistent and complete view of the aerosol macrophysics and microphysics in the UV and SWIR.



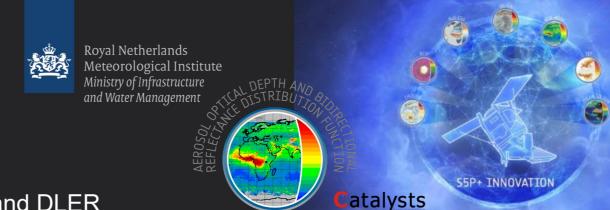






SENTINEL-5P+ INNOVATION

ESA EOP-SDR initiative (IT)



S5P-TROPOMI AER OT and DLER

THE EUROPEAN SPACE AGENCY

S5P-PAL

THE SENTINEL 5-P PRODUCT ALGORITHM LABORATORY

Welcome to your S5P-PAL workspace.

User documentation is available. If you encounter any problems or have any questions, please contact the support desk.

The following services are available for you to run:







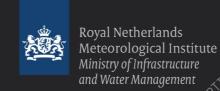


GRASP

AOT (and DLER) were developed on S5P <u>Product</u>
<u>Algorithm Laboratory</u>, developed by ESA:

- Online
- Meant to aid algorithm developers
- Fast
- Ready for implementation at PDGS (Payload Data Ground Segment)



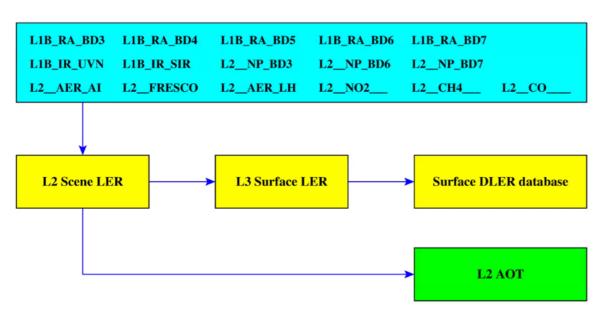


SENTINEL-5P+ INNOVATION

ESA EOP-SDR initiative (IT)

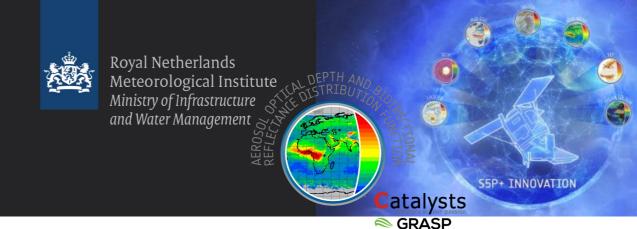
Logic behind the DLER processing on S5P-PAL:





A scene LER product is also being made for Sentinel-5/UVNS.
Since the scene LER product contains band reflectances it can also be used to generate L2 AOT.





Conclusions:

- √ AOT and DLER products are developed for S5P/TROPOMI and ready for use
- ✓ Data are validated and all documentation is ready
- ✓ Implementation on PAL resulted in very efficient data production
- √ Ready for implementation as an operational product
- ✓ More information: martin.de.graaf@knmi, tilstra@knmi.nl



